Second U.S. Patent for Specimen Preparation Methods

EXpressLO, provider of focused ion beam (FIB) ex situ lift out specimen preparation solutions, has been granted patent number 8,789,826 by the U.S. Patent and Trademark Office for specimen manipulation methods incorporating a unique specimen carrier support grid design described in U.S. Patent 8,740,209. This is the second company patent for EXpressLO LLC awarded to founder and President, Dr. Lucille A. Giannuzzi.

These complementary patents extend EXpressLO's portfolio of intellectual property. The EXpressLO carrier support grid and lift out methods for manipulating and holding site specific FIB prepared specimens allow research scientists and engineers to perform characterization and analyses by electron microscopy or other analytical instrumentation. With the patented support grids and method, lift out and manipulation of specimens are performed outside the FIB on an EXpressLO station, reducing the capital cost of specimen preparation by more than 90 percent. In addition, the newly released Pick&Place holder kit incorporates a dual pin EXpressLO grid holder and leveling device to maximize geometries used for the patented lift out process and post lift out FIB processing. The EXpressLO lift out process benefits FIB users in industry and universities in both the life sciences and physical sciences.

More information:
http://www.expresslo.com/